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HEARING AID COMPATIBILITY

Applicant Name:

LG Electronics MobileComm U.S.A. Inc. 1000 Sylvan Avenue Englewood Cliffs, NJ 07632 United States Date of Testing: 05/09/2016 - 05/11/2016 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 0Y1605060893-R1.ZNF

FCC ID:

ZNFL53AL

APPLICANT:

LG ELECTRONICS MOBILECOMM U.S.A. INC.

Scope of Test: Application Type: FCC Rule Part(s): HAC Standard: EUT Type: Model(s): Test Device Serial No.: RF Emissions Testing Certification CFR §20.19(b) ANSI C63.19-2011 Portable Handset LGL53BL, LG-L53BL, L53BL *Pre-Production Sample* [S/N: 06685]

C63.19-2011 HAC Category:

M3 (RF EMISSIONS CATEGORY)

Note: This revised Test Report (S/N: 0Y1605060893-R1.ZNF) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 1 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 1 of 66
© 2016 PCTEST Engineering Laboratory, Inc.				REV 3.1.M

1.		3
2.	EUT DESCRIPTION	4
3.	ANSI/IEEE C63.19 PERFORMANCE CATEGORIES	5
4.	SYSTEM SPECIFICATIONS	6
5.	TEST PROCEDURE	11
6.	SYSTEM CHECK	13
7.	MODULATION INTERFERENCE FACTOR	16
8.	RF CONDUCTED POWER MEASUREMENTS	19
9.	JUSTIFICATION OF HELD TO EAR MODES TESTED	28
10.	OVERALL MEASUREMENT SUMMARY	29
11.	EQUIPMENT LIST	31
12.	MEASUREMENT UNCERTAINTY	32
13.	TEST DATA	33
14.	CALIBRATION CERTIFICATES	38
15.	CONCLUSION	61
16.	REFERENCES	62
17.	TEST PHOTOGRAPHS	64

FCC ID: ZNFL53AL	H	AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 2 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 2 01 00
© 2016 PCTEST Engineering L	aboratory, Inc.			REV 3.1.M 05/09/2016

1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid *in-vitu*

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕕 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Demo 2 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 3 of 66
© 2016 PCTEST Engineering	Laboratory, Inc.			REV 3.1.M 05/09/2016

2. EUT DESCRIPTION



FCC ID:	ZNFL53AL
Manufacturer:	LG Electronics MobileComm U.S.A. Inc.
	1000 Sylvan Avenue
	Englewood Cliffs, NJ 07632
	United States
Model(s):	LGL53BL, LG-L53BL, L53BL
Serial Number:	06685
Antenna Configurations:	Internal Antenna
HAC Test Configurations:	GSM 850, 128, 190, 251, BT Off, WLAN Off, LTE Off
	GSM 1900, 512, 661, 810, BT Off, WLAN Off, LTE Off
EUT Type:	Portable Handset

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Voice over Digital Transport OTT Capability	WIFI Low Power	Additional GSM Power Reduction	
	850	VO	Yes	Yes: WIFI or BT	N/A	N/A	No	
GSM	1900	VO	res	Tes: WIFI OF BI	N/A	N/A	NO	
	GPRS/EDGE	DT	No	Yes: WIFI or BT	Yes	N/A	No	
	850							
UMTS	1700	VD	No ¹	Yes: WIFI or BT	N/A	N/A	N/A	
UIVITS	1900							
	HSPA	DT	No	Yes: WIFI or BT	Yes	N/A	N/A	
	700 (B12)	VD ³						
LTE (FDD)	850 (B5)		VD ³ No ^{1 2}	Yes: WIFI or BT	Yes	N/A	N/A	
LIE (FDD)	1700 (B4)		VD ²		NO ²	res. WIFI OF BI	res	N/A
	1900 (B2)							
WIFI	2450	VD	No ^{1 2 4}	Yes: GSM, UMTS, or LTE	Yes	N/A	N/A	
ВТ	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A	N/A	N/A	
DT = Digital Data - Not intended for CMRS Service 2. No a VD = CMRS and Data Transport 3. The 4. 2.400				or MIF and low-power exemption ed T-coil measurement has been 5076 D02 T-Coil testing for CMR oLTE CMRS service is defined by .11b/g/n modes were evaluated n held-to-ear scenarios. Detailed	made in accordance with S IP. GSMA in PRD IR.92 for IP at reduced power due to ir	Voice Service a dependent po	nd Digital Transport. wer reduction	

Table 2-1: ZNFL53AL HAC Air Interfaces

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 4 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 4 of 66
© 2016 PCTEST Engineering	Laboratory, Inc.			REV 3.1.M 05/09/2016

3. ANSI/IEEE C63.19 PERFORMANCE CATEGORIES

I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters			
Near field Category	E-field emissions CW dB(V/m)			
	f < 960 MHz			
M1	50 to 55			
M2	45 to 50			
M3	40 to 45			
M4	< 40			
	f > 960 MHz			
M1	40 to 45			
M2	35 to 40			
M3	30 to 35			
M4	< 30			
Table 3-1 WD near-field categories as defined in ANSI C63.19-2011				

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 5 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 5 01 00
© 2016 PCTEST Engineering L	aboratory, Inc.			REV 3.1.M
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4. SYSTEM SPECIFICATIONS

ER3DV6 E-Field Probe Description

Construction:	One dipole parallel, two dipoles normal to probe axis
Calibration:	Built-in shielding against static charges In air from 100 MHz to 3.0 GHz (absolute accuracy ±6.0%, k=2)
Frequency:	100 MHz to > 6 GHz;
	Linearity: ± 0.2 dB (100 MHz to 3 GHz)
Directivity	± 0.2 dB in air (rotation around probe axis)
	± 0.4 dB in air (rotation normal to probe axis)
Dynamic Range	2 V/m to > 1000 V/m
, 0	(M3 or better device readings fall well below diode
	compression point)
Linearity:	± 0.2 dB
Dimensions	Overall length: 330 mm (Tip: 16 mm)
	Tip diameter: 8 mm (Body: 12 mm)
	Distance from probe tip to dipole centers: 2.5 mm

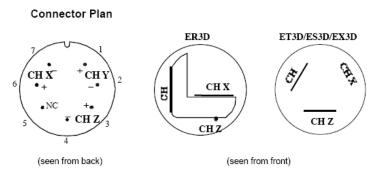


Figure 4-1 E-field Free-space Probe

Probe Tip Description

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

The electric field probes have an irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement"). Their geometric center is at 2.5mm from the tip, and the element ends are 1.1mm closer to the tip.



The antistatic shielding inside the probe is connected to the probe connector case.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Daga 6 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 6 of 66
© 2016 PCTEST Engineering	Laboratory, Inc.			REV 3.1.M 05/09/2016

Instrumentation Chain

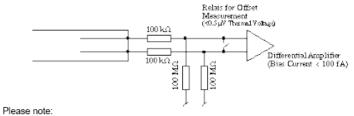
Equation 1 Conversion of Connector Voltage *u_i* to E-Field *E_i*

$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

whereby

Ei:	electric field in V/m
Uj.	voltage of channel i at the connector in μV
Norm	sensitivity of channel i in μV/(V/m) ²
ConvF:	enhancement factor in liquid (ConvF=1 for Air)
DCP:	diode compression point in µV
CF:	signal crest factor (peak power/average power)

Conditions of Calibration



a lower input impedance of the amplifier will result in different sensitivity factors Norm, and DCP

larger bias currents will cause higher offset

Probe Response to Frequency

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).

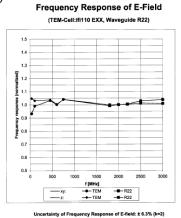


Figure 4-2 E-Field Probe Frequency Response

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Daga 7 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 7 of 66
© 2016 PCTEST Engineering	Laboratory, Inc.			REV 3.1.M 05/09/2016

SPEAG Robotic System

E-field measurements are performed using the DASY5 automated dosimetric assessment system. The DASY5 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of high precision robotics system (Staubli), robot controller, Intel CORE i7 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



Figure 4-3 SPEAG Robotic System

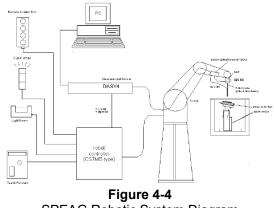
System Hardware

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the computer with operating system and RF Measurement Software DASY5 v52.8 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕑 LG	Reviewed by: Quality Manager
Filename: 0Y1605060893-R1.ZNF	Test Dates: 05/09/2016 - 05/11/2016	EUT Type: Portable Handset		Page 8 of 66
© 2016 PCTEST Engineering I	_aboratory, Inc.	·		REV 3.1.M 05/09/2016

System Electronics

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.



SPEAG Robotic System Diagram

DASY5 Instrumentation Chain

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

$$V_i = U_i + U_i^2 \cdot \frac{cf}{dcp_i}$$

with	V_i	= compensated signal of channel i	(i = x, y, z)
	U_i	= input signal of channel i	(i = x, y, z)
	cf	= crest factor of exciting field	(DASY parameter)
	dcp_i	= diode compression point	(DASY parameter)

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 9 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		1 age 3 01 00
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From the compensated input signals the primary field data for each channel can be evaluated:

$$\begin{array}{rcl} {\rm E-field probes}: & E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}} \\ {\rm with} & V_i & = {\rm compensated \ signal \ of \ channel \ i} & ({\rm i}={\rm x,\ y,\ z}) \\ & Norm_i & = {\rm sensor \ sensitivity \ of \ channel \ i} & ({\rm i}={\rm x,\ y,\ z}) \\ & \mu {\rm V}/({\rm V/m})^2 \ {\rm for \ E-field \ Probes} \\ & ConvF & = {\rm sensitivity \ enhancement \ in \ solution} \end{array}$$

 E_i = electric field strength of channel i in V/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500ms.

The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500ms and a probe response time of <5 ms. In the current implementation, DASY5 waits longer than 100ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 10 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Tage to 0100
2016 PCTEST Engineering Laboratory, Inc.				REV 3.1.M
				05/09/2016

5. TEST PROCEDURE

I. RF EMISSIONS



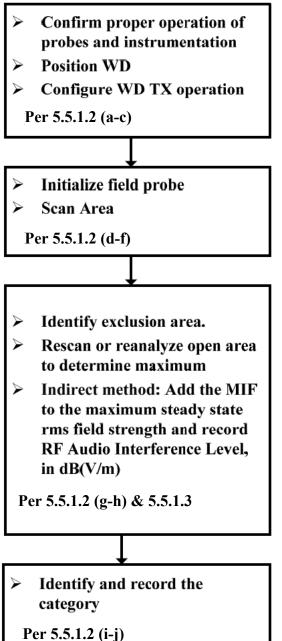
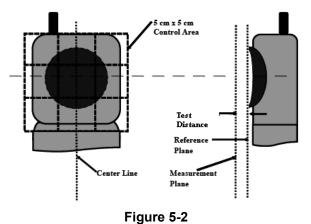


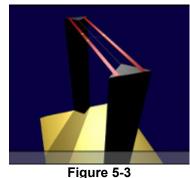
Figure 5-1 RF Emissions Flow Chart

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 11 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 11 of 66
◎ 2016 PCTEST Engineering Laboratory, Inc.				REV 3.1.M

Test Setup



E-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)



HAC Phantom

RF Emissions Test Procedure:

The following illustrate a typical RF emissions test scan over a wireless communications device:

- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm or 5mm increments in the 5 x 5 cm region were performed at a distance 15 mm from the center point of the probe measurement element to the WD. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location. If the power drift deviated by more than 5%, the HAC test and drift measurements were repeated.

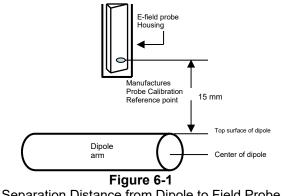
	Quality Manager	
Г Туре:	Page 12 of 66	
table Handset	Fage 12 01 00	
2016 PCTEST Engineering Laboratory, Inc.		
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6. SYSTEM CHECK

I. System Check Parameters

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 15 mm probe to dipole separation, which is measured from top surface of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device [e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (20dBm) RMS] after adjustment for any mismatch.

II. Validation Procedure

A dipole antenna meeting the requirements given in C63.19 was placed in the position normally occupied by the WD.

The length of the dipole was scanned, and the average peak value was recorded.

Measurement of CW

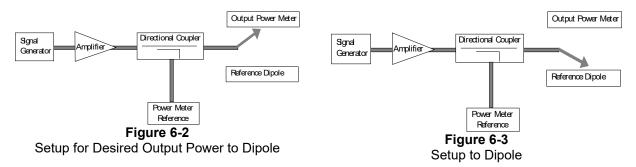
Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (see manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕕 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dama 40 af 60
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 13 of 66
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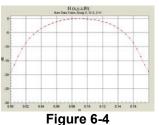
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RF power was recorded using both an average and a peak power reading meter.

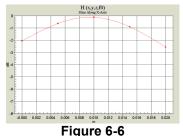


Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 6-3.

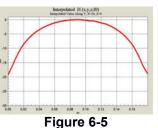
The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



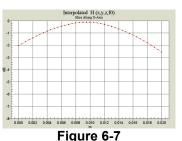
2-D Raw Data from scan along dipole axis



2-D Raw Data from scan along transverse axis



2-D Interpolated points from scan along dipole axis



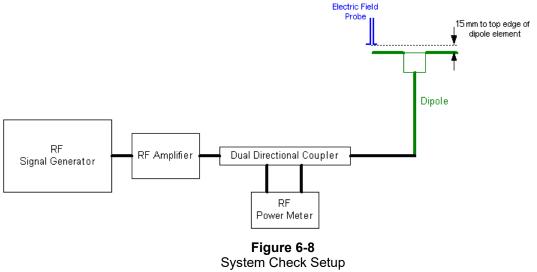
2-D Interpolated points from scan along transverse axis

V ENLINEED CARDYATENT, INC.	AC (RF EMISSIONS) TEST REPORT	🕒 LG	Quality Manager
est Dates:	EUT Type:		Dage 14 of 66
5/09/2016 - 05/11/2016	Portable Handset		Page 14 of 66
2016 PCTEST Engineering Laboratory, Inc.			REV 3.1.M 05/09/2016
2	est Dates: 5/09/2016 - 05/11/2016	EUT Type: //09/2016 - 05/11/2016 Portable Handset	EUT Type: //09/2016 - 05/11/2016 Portable Handset

III. System Check Results

Validation Results

Frequency (MHz)	Dipole S/N	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation
835	1003	20.0	108.9	106.8	1.9%
1880	1137	20.0	92.7	89.7	3.3%



FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 15 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 15 of 66
© 2016 PCTEST Engineering	2016 PCTEST Engineering Laboratory, Inc.			REV 3.1.M
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7. MODULATION INTERFERENCE FACTOR

I. Measuring Modulation Interference Factors

For any specific fixed and repeatable modulated signal, a modulation interference factor (MIF, expressed in dB) may be determined that relates its interference potential to its steady-state RMS signal level or average power level. This factor is a function only of the audio-frequency amplitude modulation characteristics of the signal and is the same for field-strength and conducted power measurements. The MIF is valid only for a specific repeatable audio-frequency amplitude modulation characteristic; any change in modulation characteristic requires determination and application of a new MIF.

The MIF may be determined using a radiated RF field or a conducted RF signal:

- a. Using RF illumination or conducted coupling, apply the specific modulated signal in question to the measurement system at a level within its confirmed operating dynamic range.
- b. Measure the steady-state RMS level at the output of the fast probe or sensor.
- c. Measure the steady-state average level at the weighting output.
- d. Without changing the square-law detector or weighting system, and using RF illumination or conducted coupling, substitute for the specific modulated signal a 1 kHz, 80% amplitude modulated carrier at the same frequency and adjust its strength until the level at the weighting output equals the step c) measurement.
- e. Without changing the carrier level from step d), remove the 1 kHz modulation and again measure the steady-state RMS level indicated at the output of the fast probe or sensor.
- f. The MIF for the specific modulation characteristic is provided by the ratio of the step e) measurement to the step b) measurement, expressed in dB (20 × log[(step e)/(step b)]).

The following procedure was used to measure the MIF using the SPEAG Audio Interference Analyzer (AIA), Type No: SE UMS 170 CB, Serial No.: 1010:

- 1. The device was placed into a simulated call using a base station simulator or set to transmit using test software for a given mode.
- 2. The device was then set to continuously transmit at maximum power.
- 3. Using a coupler if needed, the device output signal was connected to the RF In port of the AIA, which was connected to a desktop computer. Alternatively, a radiated RF signal may be used with the AIA's built-in antenna.
- 4. The MIF measurement procedure in the DASY software was run, and the resulting MIF value was recorded.
- 5. Steps 1-4 were repeated for all CMRS air interfaces, frequency bands, and modulations.

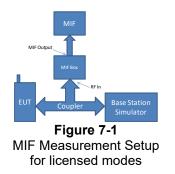
The modulation interference factors obtained were applied to readings taken of the actual wireless device in order to obtain an accurate audio interference level reading using the formula:

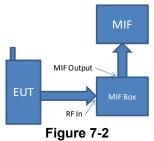
Audio Interference Level [dB(V/m)] = 20 * log[Raw Field Value (V/m)] + MIF (dB)

Because the MIF value is output power independent, MIF values for a given mode should be constant across all devices; however, per C63.19-2011 §D.7, MIF values should be measured for each device being evaluated. The voice modes for this device have been investigated in this section of the report.

	HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Test Dates:	EUT Type:		Dage 16 of 66
05/09/2016 - 05/11/2016	Portable Handset		Page 16 of 66
2016 PCTEST Engineering Laboratory, Inc.			REV 3.1.M 05/09/2016
0	Test Dates: 05/09/2016 - 05/11/2016	Test Dates: EUT Type: 05/09/2016 - 05/11/2016 Portable Handset	EUT Type: 05/09/2016 - 05/11/2016 Portable Handset

II. MIF Measurement Block Diagrams





MIF Measurement Setup for unlicensed modes

III. Measured Modulation Interference Factors:

Mode		GSM850			GSM1900	
mode	128	190	251	512	661	810
GSM	3.56	3.56	3.56	3.49	3.50	3.51

Table 7-1 GSM Modulation Interference Factors¹

Mode			UMTS V			UMTS IV			UMTS II	
IVIC	ae	4132	4183	4233	1312	1412	1513	9262	9400	9538
UMTS	12.2 kbps RMC	-25.40	-25.11	-25.15	-25.81	-25.75	-24.98	-25.79	-25.65	-25.09
010113	12.2 kbps AMR	-13.24	-13.37	-12.81	-13.36	-13.01	-12.71	-12.71	-13.12	-12.86

Table 7-2

UMTS Modulation Interference Factors¹

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
2	1880.0	18900	20	16QAM	1	0	-9.74
4	1732.5	20175	20	16QAM	1	0	-10.12
5	836.5	20525	10	16QAM	1	0	-9.80
12	707.5	20395	10	16QAM	1	0	-9.86
2	1880.0	18900	20	QPSK	1	0	-14.72
2	1880.0	18900	20	16QAM	1	50	-10.04
2	1880.0	18900	20	16QAM	1	99	-10.05
2	1880.0	18900	20	16QAM	50	0	-15.69
2	1880.0	18900	20	16QAM	100	0	-16.89
2	1880.0	18900	15	16QAM	1	0	-10.41
2	1880.0	18900	10	16QAM	1	0	-9.81
2	1880.0	18900	5	16QAM	1	0	-9.56
2	1880.0	18900	3	16QAM	1	0	-9.70
2	1880.0	18900	1.4	16QAM	1	0	-10.59
2	1857.5	18675	5	16QAM	1	0	-9.53
2	1907.5	19175	5	16QAM	1	0	-9.73

Table 7-3

LTE FDD Modulation Interference Factors^{1,2}

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

² Note: All LTE bands were found to have substantially similar MIF values given similar RB and BW configurations.

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Dogo 17 of 66	
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 17 of 66	
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	asurement	ts [dB]					
Mode	Data Rate [Mbps]						
	1	2	5.5	11			
802.11b	-15.99	-15.21	-12.02	-11.88			
Table 7-4							

802.11b (2.4GHz, SISO) Modulation Interference Factors^{1,2}

		802.11g MIF Measurements [dB]								
Mode		Data Rate [Mbps]								
	6	6 9 12 18 24 36 48 54						54		
802.11g	-14.28	-13.71	-13.07	-12.47	-11.97	-11.67	-11.84	-12.10		

Table 7-5

802.11g (2.4GHz, SISO) Modulation Interference Factors^{1,2}

	802.11n (2.4GHz) MIF Measurements [dB]								
Mode		Data Rate [Mbps]							
	6.5	13	19.5	26	39	52	58.5	65	
802.11n	-14.14	-13.00	-12.54	-11.95	-11.74	-12.03	-12.20	-12.40	

Table 7-6

802.11n (2.4GHz, SISO) Modulation Interference Factors^{1,2}

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

² Note: WLAN MIF values were found to be independent of the transmit channel.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Page 18 of 66	
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 10 01 00	
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8. RF CONDUCTED POWER MEASUREMENTS

I. Procedures Used to Establish RF Signal for HAC Testing

The handset was placed into a simulated call using a base station simulator in a shielded chamber. Such test signals offer a consistent means for testing HAC and are recommended for evaluating HAC. Measurements were taken with a fully charged battery. In order to verify that the device was tested and maintained at full power, this was configured with the base station simulator.

II. HAC Measurement Conditions

Output Power Verification

Maximum output power is verified on the High, Middle and Low channels for all applicable air interfaces. See Table 8-1 for air interface specific settings of transmit power parameters.

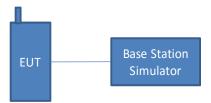
Parameter Name:	Parameter Set To:
PCL	GSM850: "5"; GSM1900: "0"
TPC	"All 1's"
TPC	"Max Power"
Mfr Configured	Mfr Specified
	PCL TPC TPC

Table 8-1

Power Control Parameters and Settings by Air Interface

III. Setup Used to Measure RF Conducted Powers

Power measurements for licensed modes were performed using a base station simulator under digital average power. Power measurements for unlicensed modes were performed using a power meter and power sensor.



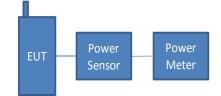


Figure 8-1 Power Measurement Setup for licensed modes

Figure 8-2 Power Measurement Setup for unlicensed modes

IV. GSM Conducted Powers

Band	Channel	GSM [dBm] CS (1 Slot)
	128	32.37
GSM 850	190	32.22
	251	32.25
	512	29.78
GSM 1900	661	29.80
	810	29.71

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 10 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 19 of 66
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REV 3.1.M 05/09/2016

V. UMTS Conducted Powers

Mode	Cellu	lar Band	[dBm]	AW	S Band [d	Bm]	PC	6 Band [d	Bm]
	4132	4183	4233	1312	1412	1513	9262	9400	9538
12.2 kbps RMC	23.57	23.65	23.65	23.30	23.62	23.62	23.22	23.67	23.46
12.2 kbps AMR	23.60	23.59	23.62	23.50	23.74	23.72	23.31	23.59	23.32

VI. LTE Conducted Powers

a. LTE Band 12

Table 8-2 LTE Band 12 (707.5MHz) Conducted Powers – 10MHz Bandwidth					
			Mid Channel		
Modulation	RB Size	RB Offset	23095 (707.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			Conducted Power [dBm]		
	1	0	24.17		0
	1	25	24.20	0	0
	1	49	23.77		0
QPSK	25	0	22.78		1
	25	12	22.79	0-1	1
	25	25	22.66		1
	50	0	22.70		1
	1	0	22.66		1
	1	25	22.92	0-1	1
	1	49	22.45		1
16QAM	25	0	21.23		2
	25	12	21.21	0-2	2
	25	25	21.20	0-2	2
	50	0	21.27		2

Note: Since LTE Band 12 at 10MHz bandwidth does not support 3 non-overlapping channels, conducted power measurements were made only on the middle channel.

Table 8-3

Modulation RB S	RB Size	RB Offset	Low Channel 23035 (701.5 MHz)	Mid Channel 23095 (707.5 MHz)	High Channel 23155 (713.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			Conducted Power	Conducted Power	Conducted Power	36FF [05]	
			[dBm]	[dBm]	[dBm]		-
	1	0	24.06	24.06	23.82		0
	1	12	24.14	24.05	23.94	0	0
	1	24	24.12	23.86	23.76		0
QPSK	12	0	22.84	22.76	22.61		1
	12	6	22.69	22.77	22.65	0-1	1
12 25	12	13	22.79	22.74	22.70		1
	25	0	22.69	22.57	22.54		1
	1	0	22.21	22.11	22.36		1
	1	12	22.50	22.25	22.22	0-1	1
	1	24	22.31	22.46	22.01		1
16QAM	12	0	21.21	21.18	21.07		2
	12	6	21.31	21.22	21.11	0-2	2
	12	13	21.32	21.19	21.11	0-2	2
	25	0	21.33	21.14	21.12		2
CC ID: ZNFL	_53AL			HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manage
ilename:		Test D	Dates:	EUT Type:			Page 20 of 66

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05/09/2016 - 05/11/2016

0Y1605060893-R1.ZNF

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Portable Handset

Page 20 of 66

REV 3.1.M

			12 (101.000112)	Ochadeted I	Owers own	E Banamati	
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	23025 (700.5 MHz)	23095 (707.5 MHz)	23165 (714.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	onducted Power [dBm	1]		
	1	0	24.00	23.90	23.87		0
	1	7	24.02	23.98	23.74	0	0
	1	14	24.13	24.08	23.81	7	0
QPSK	8	0	22.66	22.71	22.51	0-1	1
	8	4	22.72	22.76	22.56		1
	8	7	22.73	22.65	22.62		1
	15	0	22.71	22.69	22.50		1
	1	0	22.18	22.13	22.26		1
	1	7	22.32	22.12	22.56	0-1	1
	1	14	22.44	22.21	22.53		1
16QAM	8	0	21.24	21.27	21.23		2
	8	4	21.26	21.12	20.99	0-2	2
	8	7	21.46	21.14	20.87	0-2	2
	15	0	21.43	21.21	21.06	1 1	2

Table 8-4 LTE Band 12 (707.5MHz) Conducted Powers – 3MHz Bandwidth

Table 8-5

LTE Band 12 (707.5MHz) Conducted Powers – 1.4MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	23017 (699.7 MHz)	23095 (707.5 MHz)	23173 (715.3 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm	1]		
	1	0	23.82	23.81	24.00		0
	1	2	24.10	24.03	23.85		0
	1	5	23.95	23.86	24.00	0	0
QPSK	3	0	23.67	23.72	23.54	0	0
	3	2	23.89	23.77	23.62		0
	3	3	23.79	23.73	23.62		0
	6	0	22.82	22.72	22.52	0-1	1
	1	0	22.56	22.64	22.73		1
	1	2	22.46	22.47	22.49		1
	1	5	22.62	22.76	22.84	0.4	1
16QAM	3	0	22.54	22.62	22.51	0-1	1
	3	2	22.85	22.66	22.59		1
	3	3	22.40	22.52	22.59	1	1
	6	0	21.41	21.41	21.61	0-2	2

b. LTE Band 5

Table 8-6 LTE Band 5 (836.5MHz) Conducted Powers – 10MHz Bandwidth

ETE Band 5 (050.5Minz) Conducted Fowers - Towinz Bandwidth					
			Mid Channel		
Modulation	RB Size	RB Size RB Offset	20525 (836.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			Conducted Power [dBm]		
	1	0	24.05		0
	1	25	24.17	0	0
	1	49	24.20		0
QPSK	25	0	22.82		1
	25	12	22.88	0-1	1
	25	25	22.86		1
	50	0	22.83		1
	1	0	22.69		1
	1	25	22.88	0-1	1
	1	49	22.94		1
16QAM	25	0	21.70		2
	25	12	21.73	0-2	2
	25	25	21.65	0-2	2
	50	0	21.68		2

Note: Since LTE Band 5 at 10MHz bandwidth does not support 3 non-overlapping channels, conducted power measurements were made only on the middle channel.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 21 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 21 of 66
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			u 5 (050.5ivii iz)	Conducted I (Danawiath	
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	20425	20525	20625	MPR Allowed per	MPR [dB]
wouldtion	KD SIZE	KB Oliset	(826.5 MHz)	(836.5 MHz)	(846.5 MHz)	3GPP [dB]	
			C	Conducted Power [dBm]		
	1	0	23.97	24.08	23.93		0
	1	12	24.08	24.00	24.05	0	0
	1	24	24.10	24.03	24.13		0
QPSK	12	0	22.74	22.80	22.70		1
	12 12	6	22.80	22.76	22.76	0-1	1
		13	22.78	22.75	22.74		1
	25	0	22.75	22.79	22.71		1
	1	0	22.61	22.75	22.57		1
	1	12	22.80	22.74	22.76	0-1	1
	1	24	22.86	22.50	22.82		1
16QAM	12	0	21.62	21.27	21.58		2
	12	6	21.65	21.30	21.61	0-2	2
	12	13	21.70	21.25	21.50	0-2	2
	25	0	21.60	21.28	21.56		2

Table 8-7 LTE Band 5 (836.5MHz) Conducted Powers – 5MHz Bandwidth

Table 8-8

LTE Band 5 (836.5MHz) Conducted Powers – 3MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	20415 (825.5 MHz)	20525 (836.5 MHz)	20635 (847.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm	1]		
	1	0	23.90	23.90	24.01		0
	1	7	24.01	24.00	23.95	0	0
	1	14	24.03	24.00	24.00		0
QPSK	8	0	22.67	22.67	22.75		1
	8	4	22.73	22.73	22.71	0-1	1
	8	7	22.71	22.71	22.70		1
	15	0	22.68	22.68	22.74		1
	1	0	22.54	22.54	22.70		1
	1	7	22.73	22.73	22.69	0-1	1
	1	14	22.79	22.79	22.45		1
16QAM	8	0	21.55	21.55	21.22		2
	8	4	21.58	21.57	21.16	0-2	2
	8	7	21.63	21.47	21.15	0-2	2
	15	0	21.53	21.53	21.23		2

Table 8-9

LTE Band 5 (836.5MHz) Conducted Powers – 1.4MHz Bandwidth

				eenaaotea i e		Ballalla	
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	20407	20525	20643	MPR Allowed per	MPR [dB]
Modulation	KD 5126	KB Oliset	(824.7 MHz)	(836.5 MHz)	(848.3 MHz)	3GPP [dB]	
			C	Conducted Power [dBm]		
	1	0	24.04	23.97	23.91		0
	1	2	24.07	24.00	23.94		0
	1	5	24.00	24.13	23.97	0	0
QPSK	3	0	23.85	23.78	23.72	U	0
	3	2	24.05	23.98	23.92		0
	3	3	23.88	23.81	23.75		0
	6	0	22.75	22.68	22.62	0-1	1
	1	0	22.67	22.60	22.54		1
	1	2	22.82	22.75	22.69		1
	1	5	22.57	22.50	22.44	0-1	1
16QAM	3	0	22.75	22.68	22.62	0-1	1
	3	2	22.71	22.64	22.58	1	1
	3	3	22.52	22.45	22.39	1	1
	6	0	22.00	21.49	21.56	0-2	2

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕑 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 22 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 22 of 66
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c. LTE Band 4

			T I I A 4A			
			Table 8-10			
LTE Band 4 (1732.5MHz) Conducted Powers – 20MHz Bandwidth						
			Mid Channel			
Modulation	RB Size	RB Offset	20175 (1732.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]	
			Conducted Power [dBm]			
	1	0	24.10		0	
	1	50	23.97	0	0	
Γ	1	99	24.18		0	
QPSK	50	0	22.91		1	
	50	25	22.96	0-1	1	
	50	50	23.08		1	
	100	0	23.03		1	
	1	0	22.76		1	
	1	50	22.80	0-1	1	
	1	99	22.77		1	
16QAM	50	0	21.50		2	
	50	25	21.55	0-2	2	
	50	50	21.51	0-2	2	
	100	٥	21 56	1	2	

 Image: Note: Since LTE Band 4 at 20MHz bandwidth does not support 3 non-overlapping channels, conducted power measurements were made only on the middle channel.

	Table 8-11
LTE Band 4 (1732.5MH)	z) Conducted Powers – 15MHz Bandwidth

			• 、••••••••••••				
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Size RB Offset	20025 (1717.5 MHz)	20175 (1732.5 MHz)	20325 (1747.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBn	n]		
	1	0	23.64	23.78	24.07		0
	1	36	23.60	24.02	23.95	0	0
	1	74	23.77	24.06	23.96		0
QPSK	36	0	22.68	22.74	23.14	0-1	1
	36	18	22.57	22.75	22.90		1
	36	37	22.56	22.82	22.83		1
	75	0	22.56	22.91	22.93		1
	1	0	22.62	22.93	22.57		1
	1	36	22.58	22.70	22.49	0-1	1
	1	74	22.66	22.62	22.40		1
16QAM	36	0	21.12	21.28	21.46		2
	36	18	21.01	21.29	21.43	0-2	2
	36	37	21.14	21.39	21.46	0-2	2
	75	0	21.12	21.39	21.45	1	2

 Table 8-12

 LTE Band 4 (1732.5MHz) Conducted Powers – 10MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation RB S	RB Size	RB Offset	20000 (1715.0 MHz)	20175 (1732.5 MHz)	20350 (1750.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			(Conducted Power [dBm]		
	1	0	23.89	24.11	24.02		0
	1	25	23.82	24.09	24.00	0	0
	1	49	23.64	24.01	24.10		0
QPSK	25	0	22.85	22.90	23.07		1
	25	12	22.48	22.83	22.72	0-1	1
	25	25	22.54	22.84	22.82	0-1	1
	50	0	22.65	22.94	23.03		1
	1	0	22.48	22.97	22.75		1
	1	25	22.38	22.70	22.30	0-1	1
	1	49	22.82	22.48	22.49		1
16QAM	25	0	21.49	21.34	21.33		2
	25	12	21.06	21.45	21.44	0-2	2
	25	25	21.13	21.25	21.43	0-2	2
	50	0	21.40	21.55	21.45		2
CID: ZNFL53AL			TEST	HAC (RF EMISSIONS) TEST REPORT	🕑 LG	Reviewed by: Quality Manage
		Test Da	ites: 016 - 05/11/2016	EUT Type: Portable Hand	4		Page 23 of 66

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Table 8-13 LTE Band 4 (1732.5MHz) Conducted Powers – 5MHz Bandwidth

						Bunawiath	
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	19975 (1712.5 MHz)	20175 (1732.5 MHz)	20375 (1752.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm	1]		
	1	0	23.45	23.88	24.08		0
	1	12	23.72	24.14	23.80	0	0
	1	24	23.90	23.73	23.90		0
QPSK	12	0	22.10	22.61	22.85	0-1	1
	12	6	22.22	22.67	22.65		1
	12	13	22.24	22.72	22.85		1
	25	0	22.18	22.56	22.74		1
	1	0	22.30	22.28	22.75		1
	1	12	22.51	22.29	22.10	0-1	1
	1	24	22.59	22.21	22.36		1
16QAM	12	0	21.47	21.22	21.31		2
	12	6	20.95	21.17	21.19	0.2	2
	12	13	21.33	21.23	21.26	0-2	2
	25	0	21.24	21.23	21.38	1	2

Table 8-14

LTE Band 4 (1732.5MHz) Conducted Powers – 3MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	19965 (1711.5 MHz)	20175 (1732.5 MHz)	20385 (1753.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm]		
	1	0	23.44	23.83	23.75		0
	1	7	23.60	24.01	23.72	0	0
	1	14	23.46	23.81	23.74		0
QPSK	8	0	22.16	22.81	22.51	0-1	1
	8	4	22.08	22.61	22.60		1
	8	7	22.20	22.65	22.58		1
	15	0	22.10	22.48	22.55		1
	1	0	21.88	22.21	22.44		1
	1	7	22.49	22.17	22.16	0-1	1
	1	14	22.44	22.13	22.39		1
16QAM	8	0	21.10	21.27	21.13		2
	8	4	20.95	21.25	20.91	0-2	2
	8	7	21.35	21.27	20.93	0-2	2
	15	0	21.20	21.26	21.10		2

Table 8-15 LTE Band 4 (1732.5MHz) Conducted Powers – 1.4MHz Bandwidth

			+ (17 0 2 .010112)			2 Bunawiath	
			Low Channel	Mid Channel	High Channel		
Modulation RB Size	RB Size	RB Offset	19957 (1710.7 MHz)	20175 (1732.5 MHz)	20393 (1754.3 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm]			
	1	0	23.54	23.60	23.89		0
	1	2	23.51	24.15	23.85		0
	1	5	23.62	24.18	24.04	0	0
QPSK	3	0	23.75	23.61	24.06		0
	3	2	23.49	23.85	23.99		0
	3	3	23.45	23.77	23.90		0
	6	0	22.74	23.06	22.99	0-1	1
	1	0	22.70	22.87	22.77	 	1
	1	2	22.39	22.69	22.59		1
	1	5	22.56	22.70	22.30		1
16QAM	3	0	22.25	22.38	22.28		1
	3	2	21.92	22.56	22.27		1
	3	3	22.15	22.43	22.38		1
	6	0	21.40	21.46	21.33	0-2	2
FCC ID: ZNFL53AL			CTEST	HAC (RF EMISSIONS) TEST REPORT	🕑 LG	Reviewed by: Quality Manager
Filename:			Dates:	EUT Type:			Page 24 of 66
0Y160506089	93-R1.ZNF	05/09/	/2016 - 05/11/2016	Portable Hand	set		5
2016 PCTES	ST Engineerir	ng Laboratory,	Inc.				REV 3.

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d. LTE Band 2

	E		· /	Conducted Po		Danuwiutii	
Modulation	RB Size	RB Offset	Low Channel 18700 (1860.0 MHz)	Mid Channel 18900 (1880.0 MHz)	High Channel 19100 (1900.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			(Conducted Power [dBm	1]		
	1	0	23.92	23.81	24.11		0
	1	50	23.77	24.10	24.15	0	0
	1	99	23.63	23.92	23.86		0
QPSK	50	0	22.64	23.00	23.06		1
	50	25	22.68	22.94	22.81	0-1	1
	50	50	22.60	22.96	22.82		1
	100	0	22.56	22.93	22.84		1
	1	0	22.50	22.32	22.71		1
	1	50	22.62	22.55	23.08	0-1	1
	1	99	22.73	22.61	22.76		1
16QAM	50	0	21.25	21.41	21.72		2
	50	25	21.09	21.42	21.50	0-2	2
	50	50	21.07	21.33	21.49	0-2	2
	100	0	21.01	21.40	21.36		2

Table 8-16 I TE Band 2 (1880 0MHz) Conducted Powers - 20MHz Bandwidth

Table 8-17 LTE Band 2 (1880.0MHz) Conducted Powers – 15MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	18675 (1857.5 MHz)	18900 (1880.0 MHz)	19125 (1902.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm	1]		
	1	0	23.74	23.79	24.01		0
	1	36	23.61	23.78	24.13	0	0
	1	74	23.73	23.82	23.84		0
QPSK	36	0	22.40	23.01	22.92	0-1	1
	36	18	22.75	22.78	22.77		1
	36	37	22.56	22.91	22.69		1
	75	0	22.49	22.74	22.68		1
	1	0	22.52	22.09	22.48		1
	1	36	22.39	22.44	23.19	0-1	1
	1	74	22.84	22.63	22.80		1
16QAM	36	0	21.21	21.45	21.47		2
	36	18	21.14	21.40	21.42	0-2	2
	36	37	20.95	21.18	21.24	0-2	2
	75	0	21.04	21.42	21.44		2

Table 8-18 LTE Band 2 (1880.0MHz) Conducted Powers – 10MHz Bandwidth

		IE Band A		Conducted Po		2 Danuwiuth	
			Low Channel	Mid Channel	High Channel		
Nodulation	RB Size	RB Offset	18650	18900	19150	MPR Allowed per	MPR [dB]
			(1855.0 MHz) (1880.0 MHz) (1905.0 MHz)		3GPP [dB]		
			Conducted Power [dBm]				
	1	0	23.87	23.87	24.03		0
	1	25	23.42	23.78	24.01	0	0
	1	49	23.73	23.97	23.71		0
QPSK	25	0	22.40	22.84	22.76		1
	25	12	22.55	22.70	22.52	0-1	1
	25	25	22.71	22.68	22.79	0-1	1
-	50	0	22.24	22.61	22.77		1
	1	0	22.51	21.99	22.60		1
	1	25	22.21	22.49	23.00	0-1	1
	1	49	22.64	22.41	22.59		1
16QAM	25	0	21.23	21.30	21.43		2
	25	12	21.01	21.27	21.55	0-2	2
	25	25	21.10	21.28	21.15	0-2	2
	50	0	21.18	21.39	21.32		2
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0Y1605060893-R1.ZNF		05/09/2	/2016 - 05/11/2016 Portable Handset			Page 25 of 66	
2016 PCTES	ST Engineerin	g Laboratory, I	nc.				REV 3

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Table 8-19 LTE Band 2 (1880.0MHz) Conducted Powers – 5MHz Bandwidth

			<u> </u>	Conadotoa i c		Banamath	
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	18625 (1852.5 MHz)	18900 (1880.0 MHz)	19175 (1907.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			C	Conducted Power [dBm	1]		
	1	0	23.95	23.85	23.97		0
	1	12	23.34	23.79	23.79	0	0
	1	24	23.66	23.92	23.71		0
QPSK	12	0	22.39	22.90	22.75	0-1	1
	12	6	22.50	22.69	22.41		1
	12	13	22.49	22.55	22.58		1
	25	0	22.08	22.44	22.87		1
	1	0	22.42	22.02	22.66		1
	1	12	22.05	22.47	23.02	0-1	1
	1	24	22.66	22.43	22.63	1	1
16QAM	12	0	21.10	21.28	21.40		2
	12	6	21.11	21.22	21.66		2
	12	13	21.23	21.11	21.16	0-2	2
	25	0	21.03	21.51	21.12	1	2

Table 8-20 LTE Band 2 (1880.0MHz) Conducted Powers – 3MHz Bandwidth

			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	B Size RB Offset	18615 (1851.5 MHz)	18900 (1880.0 MHz)	19185 (1908.5 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			(Conducted Power [dBm	1]		
	1	0	23.72	23.91	23.84		0
	1	7	23.26	23.66	23.84	0	0
	1	14	23.41	23.89	23.73		0
QPSK	8	0	22.42	22.94	22.86		1
	8	4	22.42	22.77	22.49	0-1	1
	8	7	22.61	22.49	22.66	0-1	1
	15	0	21.84	22.45	22.62		1
	1	0	22.51	21.95	22.44		1
	1	7	21.92	22.31	22.86	0-1	1
	1	14	22.41	22.33	22.41		1
16QAM	8	0	21.23	21.07	21.54		2
	8	4	20.86	21.08	21.51	0-2	2
	8	7	21.35	21.02	20.95	0-2	2
	15	0	21.15	21.57	21.20		2

Table 8-21 LTE Band 2 (1880.0MHz) Conducted Powers – 1.4MHz Bandwidth

			. (1000.0101112)				
			Low Channel	Mid Channel	High Channel		
Modulation	RB Size	RB Offset	18607 (1850.7 MHz)	18900 (1880.0 MHz)	19193 (1909.3 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
			Conducted Power [dBm]				
	1	0	23.69	23.81	24.03		0
	1	2	23.83	23.83	24.16		0
	1	5	23.67	23.90	23.92	0	0
QPSK	3	0	23.65	23.94	23.60		0
	3	2	23.66	23.91	23.53		0
	3	3	23.68	23.89	23.62		0
	6	0	22.69	22.84	22.75	0-1	1
	1	0	22.52	22.70	22.56		1
	1	2	22.50	23.00	22.95	0-1	1
	1	5	22.56	22.72	22.97		1
16QAM	3	0	22.33	22.43	22.70		1
	3	2	22.52	22.44	22.92		1
	3	3	22.54	22.54	22.58		1
	6	0	21.43	21.44	21.31	0-2	2
FCC ID: ZNFL53AL			CTEST H	AC (RF EMISSIONS)	TEST REPORT	🕕 LG	Reviewed by: Quality Manager
		Test Da		EUT Type:			Page 26 of 66
		05/09/2	016 - 05/11/2016	Portable Hands	Portable Handset		1 490 20 01 00
2016 PCTES	ST Engineerin	g Laboratory, I	nc.				REV 3

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05/09/2016

VII. WLAN Conducted Powers

IEEE 802.11b/g/n (2.4GHz, SISO) Average RF Power										
	2.4GHz Conducted Pow									
Freq [MHz]	Channel	IEEE Transmission Mode 802.11b 802.11g 802.11n								
2412	1	14.99	13.27	12.97						
2417	2	15.06	14.34	14.13						
2437	6	14.66	14.26	13.98						
2475	10	14.93 14.33 14.01								
2462	11	15.16	12.33	11.94						

Table 8-22

*This device operates at reduced power due to independent power reduction mechanisms for the WLAN transmitter in 802.11b/g/n modes for held-to-ear scenarios.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕑 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 07 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 27 of 66
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9. JUSTIFICATION OF HELD TO EAR MODES TESTED

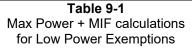
I. Analysis of RF Air Interface Technologies

- **a.** According to the April 2013 TCB workshop slides, OTT data services are outside the current definition of a managed CMRS service and are currently not required to be evaluated.
- b. No associated T-coil measurements for VoLTE or VoIP over WIFI CMRS have been made in accordance with the guidance issued by OET in KDB publication 285076 D02 T-Coil testing for CMRS IP.
- c. An analysis was performed, following the guidance of §4.3 and §4.4 of the ANSI standard, of the RF air interface technologies being evaluated. The factors that will affect the RF interference potential were evaluated, and the worst case operating modes were identified and used in the evaluation. A WD's interference potential is a function both of the WD's average near-field field strength and of the signal's audio-frequency amplitude modulation characteristics. Per §4.4, RF air interface technologies that have low power have been found to produce sufficiently low RF interference potential, so it is possible to exempt them from the product testing specified in Clause 5 of the ANSI standard. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is ≤17dBm for all of its operating modes. RF air interface technologies exempted from testing in this manner are automatically assigned an M4 rating to be used in determining the overall rating for the WD.

The worst case MIF plus the worst case average antenna input power for all modes are investigated below to determine the testing requirements for this device.

Air Interface	Maximum Average Power (dBm)	Worst Case MIF (dB)	Total (Power + MIF, dB)	C63.19 Testing Required
GSM850	23.34*	3.56	26.90	Yes
GSM1900	20.77*	3.51	24.28	Yes
UMTS - RMC	23.67	-24.98	-1.31	No
UMTS - AMR	23.74	-12.71	11.03	No
LTE - FDD	24.20	-9.53	14.67	No
2.4GHz WLAN	15.16	-11.67	3.49	No

II. Individual Mode Evaluations



* Note: C63.19 Footnote 20 (pg.13) indicates the use of a long averaging time for measuring the antenna input power when using this method of exclusion. Therefore, the frame averaged power was calculated for these modes in this investigation.

III. Low-Power Exemption Conclusions

Per ANSI C63.19-2011, RF Emissions testing for this device is required only for GSM voice modes. All other air interfaces are exempt.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 28 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 20 01 00
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10. OVERALL MEASUREMENT SUMMARY

FCC ID:	ZNFL53AL
Model:	LGL53BL, LG-L53BL, L53BL
S/N:	06685

I. E-FIELD EMISSIONS:

	HAC Data Summary for E-field											
Mode	Channel	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC MARGIN (dB)	RESULT	Excl Blocks per 5.5	
E-field Emis	sions											
GSM850	128	Acoustic	32.37	56.82	35.09	3.56	38.65	45.00	-6.35	M4	none	
GSM850	190	Acoustic	32.22	58.22	35.30	3.56	38.86	45.00	-6.14	M4	none	
GSM850	251	Acoustic	32.25	57.30	35.16	3.56	38.72	45.00	-6.28	M4	none	
GSM1900	512	Acoustic	29.78	22.45	27.02	3.49	30.51	35.00	-4.49	M3	7,8,9	
GSM1900	661	Acoustic	29.80	26.03	28.31	3.50	31.81	35.00	-3.19	M3	7,8,9	
GSM1900	810	Acoustic	29.71	25.02	27.97	3.51	31.48	35.00	-3.52	M3	7,8,9	
GSM1900	661	T-coil	29.80	28.35	29.05	3.50	32.55	35.00	-2.45	M3	none	

Table 10-1 HAC Data Summary for E-field

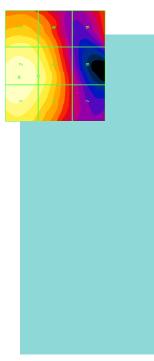


Figure 10-1

Sample E-field Scan Overlay (T-Coil Centered Scan area pictured. See Test Setup Photographs for actual WD overlay and Acoustic Centered Scan Area.)

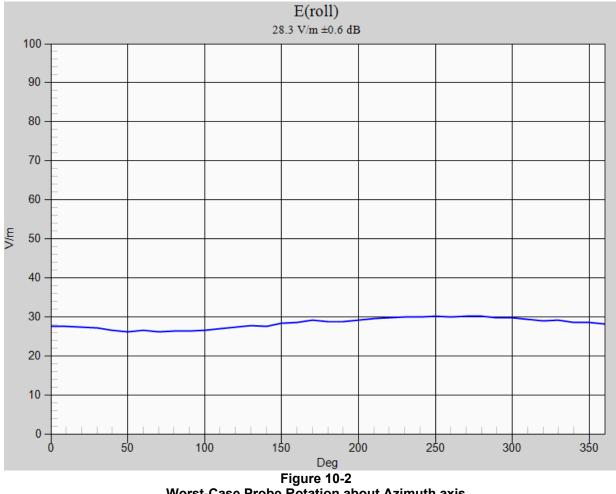
FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 29 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		1 age 23 01 00
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FCC ID:	ZNFL53AL
Model:	LGL53BL, LG-L53BL, L53BL
S/N:	06685

II. Worst-case Configuration Evaluation

	Peak Reading 360° Probe Rotation at Azimuth axis										
Mode	Channel	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC MARGIN (dB)	RESULT		
Probe Rotatio	Probe Rotation at Worst-Case										
GSM1900	661	T-coil	30.10	29.57	3.50	33.07	35.00	-1.93	M3		

Table 10-2



Worst-Case Probe Rotation about Azimuth axis

* Note: Locations of probe rotation (with and without exclusions) are shown in Figure 10-1 denoted by the green square markers.

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 30 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 50 01 00
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11. EQUIPMENT LIST

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4438C	ESG Vector Signal Generator	3/4/2015	Biennial	3/4/2017	MY45090555
Agilent	N5182A	MXG Vector Signal Generator	11/6/2015	Annual	11/6/2016	MY47420603
Amplifier Research	15S1G6	Amplifier	N/A	CBT*	N/A	433978
Anritsu	ML2495A	Power Meter	10/16/2015	Biennial	10/16/2017	941001
Anritsu	MA2411B	Pulse Power Sensor	10/14/2015	Biennial	10/14/2017	846215
Anritsu	MA24106A	USB Power Sensor	5/29/2015	Annual	5/29/2016	1244512
Anritsu	MA24106A	USB Power Sensor	5/29/2015	Annual	5/29/2016	1248508
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	N/A	CBT*	N/A	1226
Pasternack	PE2237-20	Bidirectional Coupler	N/A	CBT*	N/A	N/A
Pasternack	NC-100	Torque Wrench	5/21/2015	Biennial	5/21/2017	N/A
Rohde & Schwarz	CMW500	Radio Communication Tester	9/8/2015	Annual	9/8/2016	109366
Rohde & Schwarz	CMU200	Base Station Simulator	12/2/2015	Annual	12/2/2016	833855/0010
SPEAG	AIA	Audio Interference Analzyer	N/A	CBT*	N/A	1010
SPEAG	CD1880V3	Freespace 1880 MHz Dipole	2/17/2015	Biennial	2/17/2017	1137
SPEAG	CD835V3	Freespace 835 MHz Dipole	2/18/2015	Biennial	2/18/2017	1003
SPEAG	ER3DV6	Freespace E-field Probe	8/24/2015	Annual	8/24/2016	2335
SPEAG	DAE4	Dasy Data Acquisition Electronics	11/11/2015	Annual	11/11/2016	1334

Table 11-1 Equipment List

Calibration traceable to the National Institute of Standards and Technology (NIST).

*Note: CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 31 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage ST 01 00
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12. MEASUREMENT UNCERTAINTY

Wireless Communications Device Near-Field Measurement Uncertainty Estimation									
Uncertainty Component	Data (dB)	Data Type	Prob. Dist.	Divisor	Ci (E)	Unc. (dB)	Notes/Comments		
Measurement System									
RF System Reflections	0.50	Tolerance	Ν	1.00	1	0.50	* Refl. < -20 dB		
Field Probe Calibration	0.21	Tolerance	Ν	1.00	1	0.21			
Field Probe Isotropy	0.01	Tolerance	Ν	1.00	1	0.01			
Field Probe Frequency Response	0.135	Tolerance	Ν	1.00	1	0.14			
Field Probe Linearity	0.013	Tolerance	Ν	1.00	1	0.01			
Modulation Interference Factor	0.20	Tolerance	R	1.73	1	0.12	Applicable for M-rating testing		
Boundary Effects	0.105	Accuracy	R	1.73	1	0.06	*		
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	1	0.12	*		
Probe Positioner	0.050	Accuracy	R	1.73	1	0.03	*		
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	1	0.03	*		
Resolution to 2mm error	0.21	Tolerance	Ν	1.00	1	0.21			
System Detection Limit	0.05	Tolerance	R	1.73	1	0.03	*		
Readout Electronics	0.015	Tolerance	Ν	1.00	1	0.02	*		
Integration Time	0.11	Tolerance	R	1.73	1	0.06	*		
Response Time	0.033	Tolerance	R	1.73	1	0.02	*		
Phantom Thickness	0.10	Tolerance	R	1.73	1	0.06	*		
System Repeatability (Field x 2=power)	0.17	Tolerance	Ν	1.00	1	0.17	*		
Test Sample Related									
Device Positioning Vertical	0.2	Tolerance	R	1.73	1	0.12	*		
Device Positioning Lateral	0.045	Tolerance	R	1.73	1	0.03	*		
Device Holder and Phantom	0.1	Tolerance	R	1.73	1	0.06	*		
Power Drift	0.21	Tolerance	R	1.73	1	0.12			
Combined Standard Uncertainty (k=1)		-	-			0.66	16.3%		
Expanded Uncertainty [95% confidence]						1.31	32.6%		
Expanded Uncertainty [95% confidence]	on Field					0.66	16.3%		

Table 12-1

Uncertainty Estimation Table

Notes:

- 1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.
- 2. * Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurements to identify the measurement uncertainty. By and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 22 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 32 of 66
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13. TEST DATA

See following Attached Pages for Test Data.

FCC ID: ZNFL53AL	HA	AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 22 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 33 of 66
© 2016 PCTEST Engineering L	REV 3.1.M 05/09/2016			

Date: 05/09/2016



PCTEST Hearing-Aid Compatibility Facility

DUT: CD835V3 - SN1003

Type: CD835V3 Serial: 1003

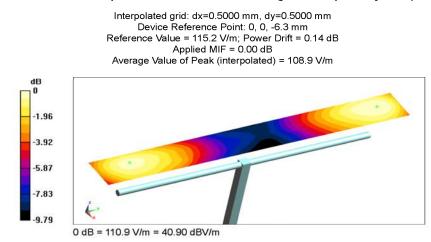
Communication System: CW; Frequency: 835 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: ER3DV6 SN2335; Calibrated: 08/24/2015
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1334; Calibrated: 11/11/2015
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.8 (8);

835 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x361x1):



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FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 24 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 34 of 66
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PCTEST Hearing-Aid Compatibility Facility

DUT: CD1880V3 - SN1137

Type: CD1880V3 Serial: 1137

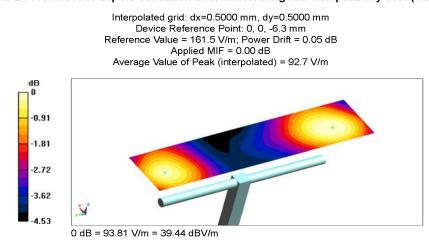
Communication System: CW; Frequency: 1880 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: ER3DV6 SN2335; Calibrated: 08/24/2015
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1334; Calibrated: 11/11/2015
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.8 (8);

1880 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):



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FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 35 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		5
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Date: 05/11/2016



PCTEST Hearing-Aid Compatibility Facility

DUT: ZNFL53AL

Type: Portable Handset Serial: 06685 Backlight off Duty Cycle: 1:8.3

Communication System: GSM; Frequency: 836.6 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

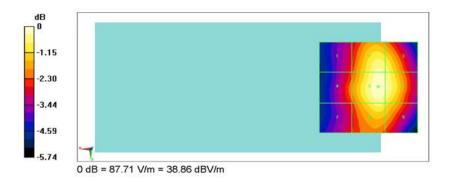
- Probe: ER3DV6 SN2335; Calibrated: 08/24/2015
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1334; Calibrated: 11/11/2015
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.8 (8);

GSM850 Mid Channel, Acoustic Centered Scan /Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 79.14 V/m; Power Drift = -0.16 dB Applied MIF = 3.56 dB RF audio interference level = 38.86 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
36.4 dBV/m	38.58 dBV/m	38.37 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
36.89 dBV/m	38.86 dBV/m	38.6 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
36.4 dBV/m	38.31 dBV/m	37.97 dBV/m



2016 PCTEST

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 36 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 30 01 00
© 2016 PCTEST Engineering L	REV 3.1.M 05/09/2016			

Date: 05/11/2016



PCTEST Hearing-Aid Compatibility Facility

DUT: ZNFL53AL

Type: Portable Handset Serial: 06685 Backlight off Duty Cycle: 1:8.3

Communication System: GSM; Frequency: 1880 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

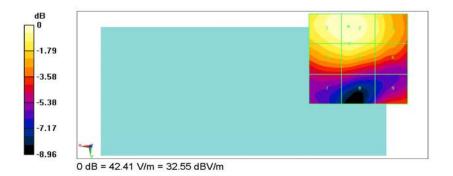
- Probe: ER3DV6 SN2335; Calibrated: 08/24/2015
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1334; Calibrated: 11/11/2015
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.8 (8);

GSM1900 Mid Channel, T-Coil Centered Scan /Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 28.44 V/m; Power Drift = -0.13 dB Applied MIF = 3.50 dB RF audio interference level = 32.55 dBV/m Emission category: M3

MIF scaled E-field

Grid 1 M3	Grid 2 M3	Grid 3 M3
32.48 dBV/m	32.55 dBV/m	31.6 dBV/m
Grid 4 M3	Grid 5 M3	Grid 6 M3
31.76 dBV/m	31.86 dBV/m	31.01 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
27 99 dBV/m	27 91 dBV/m	29.03 dBV/m



2016 PCTEST

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 37 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 37 01 00
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14. CALIBRATION CERTIFICATES

The following pages include the probe calibration used to evaluate HAC for the DUT.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager		
Filename:	Test Dates:	EUT Type:		Dage 29 of 66		
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 38 of 66		
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Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client PC Test

Certificate No: ER3-2335_Aug15/2

Dbject	ER3DV6 - SN:23	35	
Calibration procedure(s)	QA CAL-02.v8, Q Calibration proce evaluations in air	A CAL-25.v6 dure for E-field probes optimized f	or close near field
Calibration date:	August 24, 2015		\mathcal{A}
	•	onal standards, which realize the physical units obability are given on the following pages and	
		y facility: environment temperature (22 \pm 3)°C a	and humidity < 70%.
Calibration Equipment used (M8	kTE critical for calibration)		
Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E44198	GB41293874	01-Apr-15 (No. 217-02128)	Mar-16
ower sensor E4412A	MY41498087	01-Apr-15 (No. 217-02128)	Mar-16
Reference 3 dB Attenuator	SN: S5054 (3c)	01-Apr-15 (No. 217-02129)	Mar-16
Reference 20 dB Attenuator	SN: S5277 (20x)	01-Apr-15 (No. 217-02132)	Mar-16
Reference 30 dB Attenuator	SN: S5129 (30b)	01-Apr-15 (No. 217-02133)	Mar-16
Reference Probe ER3DV6	SN: 2328	08-Oct-14 (No. ER3-2328_Oct14)	Oct-15
DAE4	SN: 789	16-Mar-15 (No. DAE4-789_Mar15)	Mar-16
Secondary Standards	ID	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Apr-13)	In house check: Apr-16
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-14)	In house check: Oct-15
	Name	Function	Signature
	Name Jeton Kastrati	Function Leboratory Technician	Signature
Calibrated by:	and a start of the	化化物 化生产的 化化化物 化化化物 建化物 医外外的 医子宫的 医结合的 网络拉拉斯 化分子 化化化物 化化化物 经收益公司	Signature
Calibrated by:	Jeton Kastrati	Laboratory Technician	Signature

Certificate No: ER3-2335_Aug15/2

Page 1 of 10

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 39 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 39 01 00
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Glossary:

 NORMx,y,z
 sens

 DCP
 diode

 CF
 crest

 A, B, C, D
 modi

 Polarization φ
 φ rot

 Polarization θ
 θ rot

sensitivity in free space diode compression point crest factor (1/duty_cycle) of the RF signal modulation dependent linearization parameters φ rotation around probe axis 9 rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., 9 = 0 is normal to probe axis e information used in DASY system to align probe sensor X to the robot coordinate system

Connector Angle

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
- b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.0, November 2013

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization 9 = 0 for XY sensors and 9 = 90 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip
 (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: ER3-2335_Aug15/2

Page 2 of 10

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename:	Test Dates:	EUT Type:		Dage 40 of 66	
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 40 of 66	
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August 24, 2015

Probe ER3DV6

SN:2335

Manufactured: Calibrated: September 9, 2003 August 24, 2015

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Calibrated for DASY/EASY Systems (Note: non-compatible with DASY2 system!)

Certificate No: ER3-2335_Aug15/2

Page 3 of 10

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager		
Filename: 0Y1605060893-R1.ZNF	Test Dates: 05/09/2016 - 05/11/2016	EUT Type: Portable Handset		Page 41 of 66		
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August 24, 2015

DASY/EASY - Parameters of Probe: ER3DV6 - SN:2335

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm (μV/(V/m) ²)	1.65	1.67	1.88	± 10.1 %
DCP (mV) ^B	100.3	99.3	100.2	

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Modulation Calibration Parameters

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Unc ^E (k=2)
0	CW	X	0.0	0.0	1.0	0.00	203.0	±3.3 %
		Y	0.0	0.0	1.0		160.6	
		Z	0.0	0.0	1.0		203.5	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^B Numerical linearization parameter: uncertainty not required.
^E Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

Certificate No: ER3-2335_Aug15/2

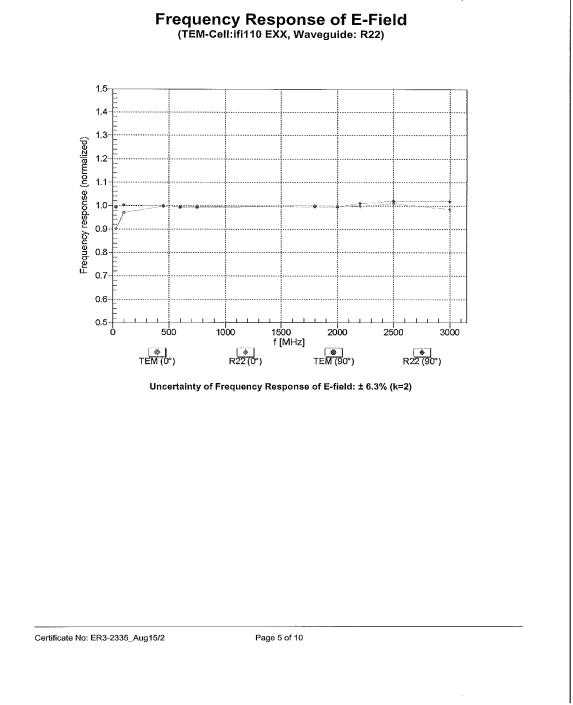
Page 4 of 10

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 42 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 42 01 00
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05/09/2016



August 24, 2015

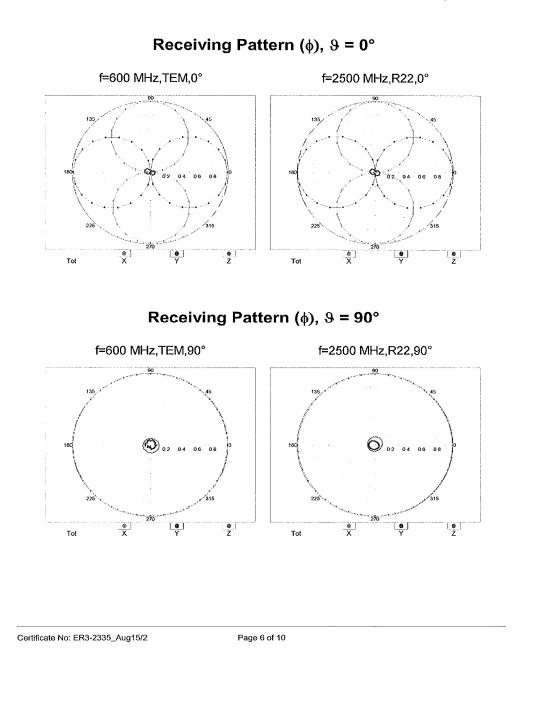


FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager		
Filename:	Test Dates:	EUT Type:		Page 43 of 66		
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 45 01 00		
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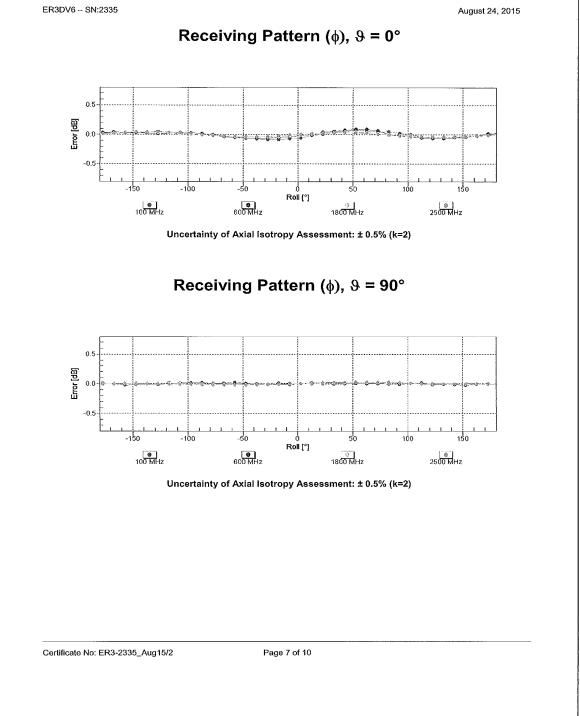
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FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 44 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 44 01 00
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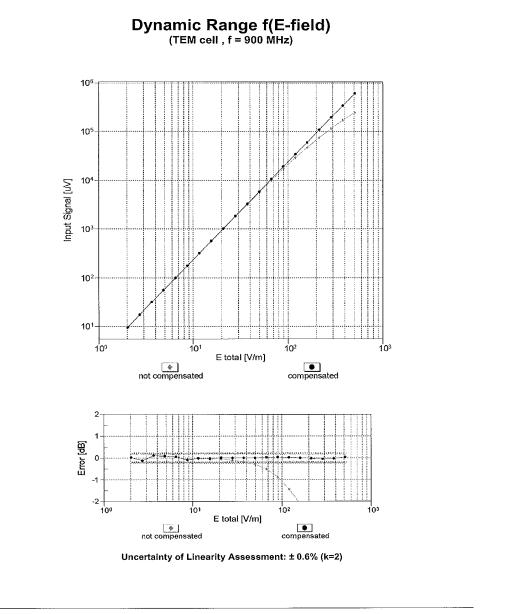


FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename: 0Y1605060893-R1.ZNF	Test Dates: 05/09/2016 - 05/11/2016	EUT Type: Portable Handset		Page 45 of 66
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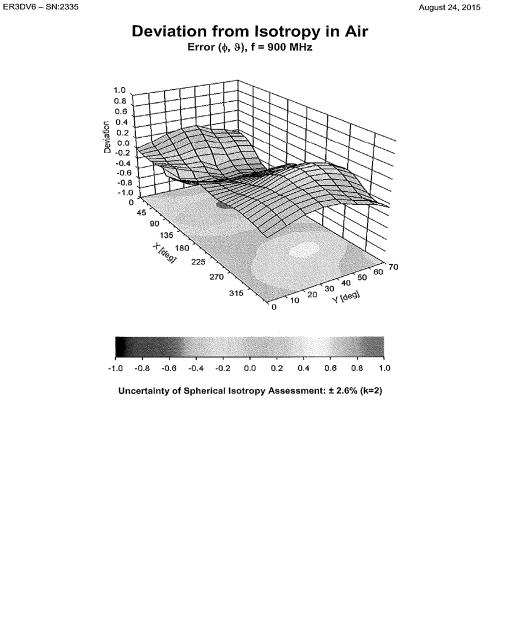
Page 8 of 10

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 46 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 46 of 66
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August 24, 2015



Certificate No: ER3-2335_Aug15/2

Page 9 of 10

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 47 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 47 01 00
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August 24, 2015

DASY/EASY - Parameters of Probe: ER3DV6 - SN:2335

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Other Probe Parameters

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Sensor Arrangement	Rectangular
Connector Angle (°)	82.7
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	10 mm
Tip Diameter	8 mm
Probe Tip to Sensor X Calibration Point	2.5 mm
Probe Tip to Sensor Y Calibration Point	2.5 mm
Probe Tip to Sensor Z Calibration Point	2.5 mm

Certificate No: ER3-2335_Aug15/2

Page 10 of 10

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager	
Filename: 0Y1605060893-R1.ZNF	Test Dates: 05/09/2016 - 05/11/2016	EUT Type: Portable Handset		Page 48 of 66	
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 Swiss Calibration Service

Accreditation No.: SCS 0108

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Client PC Test

Certificate No: CD835V3-1003_Feb15

Object	CD835V3 - SN: 1003					
Calibration procedure(s)	QA CAL-20.v6 Calibration procedure for dipoles in air					
Calibration date:	February 18, 201	5				
	· · · · · · · · · · · · · · · · · · ·	-				
The measurements and the unc	ertainties with confidence p	onal standards, which realize the physical units robability are given on the following pages and y facility: environment temperature $(22 \pm 3)^{\circ}$ C	are part of the certificate.			
Calibration Equipment used (M8						
Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration			
Power meter EPM-442A	GB37480704	07-Oct-14 (No. 217-02020)	Oct-15			
Power sensor HP 8481A	US37292783	07-Oct-14 (No. 217-02020)	Oct-15			
Power sensor HP 8481A	MY41092317	07-Oct-14 (No. 217-02021)	Oct-15			
Reference 10 dB Attenuator	SN: 5047.2 / 06327	03-Apr-14 (No. 217-01921)	Apr-15			
Probe ER3DV6	SN: 2336	31-Dec-14 (No. ER3-2336_Dec14)	Dec-15			
Probe H3DV6	SN: 6065	31-Dec-14 (No. H3-6065_Dec14)	Dec-15			
DAE4	SN: 781	12-Sep-14 (No. DAE4-781_Sep14)	Sep-15			
Secondary Standards	ID #	Check Date (in house)	Scheduled Check			
Power meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Sep-14)	In house check: Sep-16			
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Sep-14)	In house check: Sep-16			
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Sep-14)	In house check: Sep-16			
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-14)	In house check: Oct-15			
RF generator R&S SMT-06	SN: 832283/011	27-Aug-12 (in house check Oct-13)	In house check: Oct-16			
	Name	Function	Signature			
Calibrated by:	Leif Klysner	Laboratory Technician	Sef Men			
	Fin Bomholt	Deputy Technical Manager	Sil My			
Approved by:						
		full without written approval of the laboratory.	Issued: February 19, 2015			

 FCC ID: ZNFL53AL
 Test Dates:
 EUT Type:
 Page 49 of 66

 0Y1605060893-R1.ZNF
 05/09/2016 - 05/11/2016
 Portable Handset
 Page 49 of 66

REV 3.1.M 05/09/2016

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



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Accreditation No.: SCS 0108

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The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of callbration certificates

References

[1]

ANSI-C63.19-2011

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: CD835V3-1003_Feb15

Page 2 of 5

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 50 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 50 of 66
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Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.8.8
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 835 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	107.6 V/m = 40.64 dBV/m	
Maximum measured above low end	100 mW input power	106.0 V/m = 40.51 dBV/m	
Averaged maximum above arm	100 mW input power	106.8 V/m ± 12.8 % (k=2)	

Appendix (Additional assessments outside the scope of SCS0108)

Antenna Parameters

Frequency	Return Loss	Impedance	
800 MHz	17.6 dB	43.4 Ω - 10.4 jΩ	
835 MHz	26.7 dB	49.8 Ω + 4.6 jΩ	
900 MHz	17.6 dB	56.3 Ω - 12.6 jΩ	
950 MHz	19.2 dB	51.5 Ω + 11.1 jΩ	
960 MHz	13.6 dB	62.2 Ω + 20.5 jΩ	

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

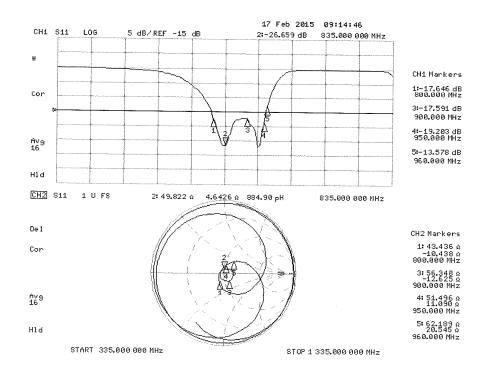
Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD835V3-1003_Feb15

Page 3 of 5

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 51 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 51 of 66
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Certificate No: CD835V3-1003_Feb15

Page 4 of 5

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕕 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dego 52 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 52 of 66
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DASY5 E-field Result

Date: 17.02.2015

Test Laboratory: SPEAG Lab2

DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1003

 $\begin{array}{l} Communication \ System: \ UID \ 0 - CW \ ; \ Frequency: \ 835 \ MHz \\ Medium \ parameters \ used: \ \sigma = 0 \ S/m, \ \epsilon_r = 1; \ \rho = 1000 \ kg/m^3 \\ Phantom \ section: \ RF \ Section \\ Measurement \ Standard: \ DASY5 \ (IEEE/IEC/ANSI \ C63.19-2011) \end{array}$

DASY52 Configuration:

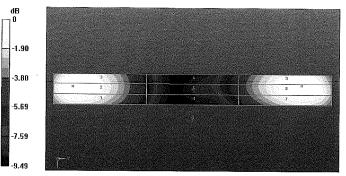
- Probe: ER3DV6 SN2336; ConvF(1, 1, 1); Calibrated: 31.12.2014;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 12.09.2014
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 121.2 V/m; Power Drift = 0.02 dB

Applied MIF = 0.00 dB RF auto interference level = 40.64 dBV/m Emission category: M3

MIF scaled E-field

		Grid 3 M3
40.26 dBV/m	40.64 dBV/m	40.58 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
35.64 dBV/m	36.04 dBV/m	36.03 dBV/m
Grid 7 M3	Grid 8 M3	Grid 9 M3
40.15 dBV/m	40.51 dBV/m	40.5 dBV/m



0 dB = 107.6 V/m = 40.64 dBV/m

Certificate No: CD835V3-1003_Feb15

Page 5 of 5

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Dage 52 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 53 of 66
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05/09/2016

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	CERTIFICAT		
Object	CD1880V3 - SN	: 1137	
Calibration procedure(s)	QA CAL-20.v6 Calibration proce	edure for dipoles in air	$\underset{3}{\overset{\circ}{\overset{\circ}}}$
			Δ <i>η</i> ι
Calibration date:	February 17, 20 ⁻	15	
The measurements and the unc	certainties with confidence p ucted in the closed laborato	ional standards, which realize the physical units robability are given on the following pages and ny facility: environment temperature (22 ± 3)°C	are part of the certificate.
Calibration Equipment used (Ma	1		
Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Power meter EPM-442A	GB37480704	07-Oct-14 (No. 217-02020)	Oct-15
Power sensor HP 8481A	US37292783	07-Oct-14 (No. 217-02020)	Oct-15
	MY41092317	07-Oct-14 (No. 217-02021)	Oct-15
Power sensor HP 8481A			
Reference 10 dB Attenuator	SN: 5047.2 / 06327	03-Apr-14 (No. 217-01921)	Apr-15
Reference 10 dB Attenuator Probe ER3DV6	SN: 2336	31-Dec-14 (No. ER3-2336_Dec14)	Dec-15
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6	SN: 2336 SN: 6065	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14)	Dec-15 Dec-15
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6	SN: 2336	31-Dec-14 (No. ER3-2336_Dec14)	Dec-15
Reference 10 dB Attenuator	SN: 2336 SN: 6065	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14)	Dec-15 Dec-15
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4	SN: 2336 SN: 6065 SN: 781	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14)	Dec-15 Dec-15 Sep-15
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards	SN: 2336 SN: 6065 SN: 781	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house)	Dec-15 Dec-15 Sep-15 Scheduled Check
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B	SN: 2336 SN: 6065 SN: 781 ID # SN: GB42420191	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 09-Oct-09 (in house check Sep-14)	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A	SN: 2336 SN: 6065 SN: 781 ID # SN: GB42420191 SN: US38485102	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 09-Oct-09 (in house check Sep-14) 05-Jan-10 (in house check Sep-14)	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16 In house check: Sep-16
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A Network Analyzer HP 8753E	SN: 2336 SN: 6065 SN: 781 ID # SN: GB42420191 SN: US38485102 SN: US37295597	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (In house) 09-Oct-09 (in house check Sep-14) 05-Jan-10 (in house check Sep-14) 09-Oct-09 (in house check Sep-14)	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16 In house check: Sep-16 In house check: Sep-16
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A	SN: 2336 SN: 6065 SN: 781 D # SN: GB42420191 SN: US38485102 SN: US37295597 US37390585	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 09-Oct-09 (in house check Sep-14) 05-Jan-10 (in house check Sep-14) 09-Oct-09 (in house check Sep-14) 09-Oct-09 (in house check Sep-14) 18-Oct-01 (in house check Oct-14)	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16 In house check: Sep-16 In house check: Sep-16 In house check: Oct-15
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A Network Analyzer HP 8753E	SN: 2336 SN: 6065 SN: 781 D # SN: GB42420191 SN: US38485102 SN: US37295597 US37390585 SN: 832283/011	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 09-Oct-09 (in house check Sep-14) 05-Jan-10 (in house check Sep-14) 09-Oct-09 (in house check Sep-14) 18-Oct-01 (in house check Cot-14) 27-Aug-12 (in house check Oct-13) Function	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16 In house check: Sep-16 In house check: Sep-16 In house check: Sep-16 In house check: Oct-15 In house check: Oct-16 Signature
Reference 10 dB Attenuator Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A Network Analyzer HP 8753E RF generator R&S SMT-06	SN: 2336 SN: 6065 SN: 781 D # SN: GB42420191 SN: US38485102 SN: US37295597 US37390585 SN: 832283/011 Name	31-Dec-14 (No. ER3-2336_Dec14) 31-Dec-14 (No. H3-6065_Dec14) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 09-Oct-09 (in house check Sep-14) 05-Jan-10 (in house check Sep-14) 09-Oct-09 (in house check Sep-14) 18-Oct-01 (in house check Cot-14) 27-Aug-12 (in house check Oct-13) Function	Dec-15 Dec-15 Sep-15 Scheduled Check In house check: Sep-16 In house check: Sep-16 In house check: Sep-16 In house check: Oct-15 In house check: Oct-15

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Daga 54 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 54 of 66
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REV 3.1.M 05/09/2016

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References

[1] ANSI-C63.19-2011

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: CD1880V3-1137_Feb15

Page 2 of 7

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Daga EE af 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 55 of 66
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Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.8.8
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	1730 MHz ± 1 MHz 1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 1730 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	98.8 V/m = 39.90 dBV/m
Maximum measured above low end	100 mW input power	93.2 V/m = 39.39 dBV/m
Averaged maximum above arm	100 mW input power	96.0 V/m ± 12.8 % (k=2)

Maximum Field values at 1880 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	90.2 V/m = 39.10 dBV/m
Maximum measured above low end	100 mW input power	89.1 V/m = 38.99 dBV/m
Averaged maximum above arm	100 mW input power	89.7 V/m ± 12.8 % (k=2)

Certificate No: CD1880V3-1137_Feb15

Page 3 of 7

FCC ID: ZNFL53AL		AC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 56 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		1 age 60 61 60
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Appendix (Additional assessments outside the scope of SCS0108)

Antenna Parameters

Nominal Frequencies

Frequency	Return Loss	Impedance
1730 MHz	22.8 dB	48.5 Ω + 7.0 jΩ
1880 MHz	21.6 dB	49.8 Ω + 8.3 jΩ
1900 MHz	21.7 dB	53.0 Ω + 7.9 jΩ
1950 MHz	27.3 dB	54.5 Ω - 0.7 jΩ
2000 MHz	19.7 dB	40.7 Ω - 0.5 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

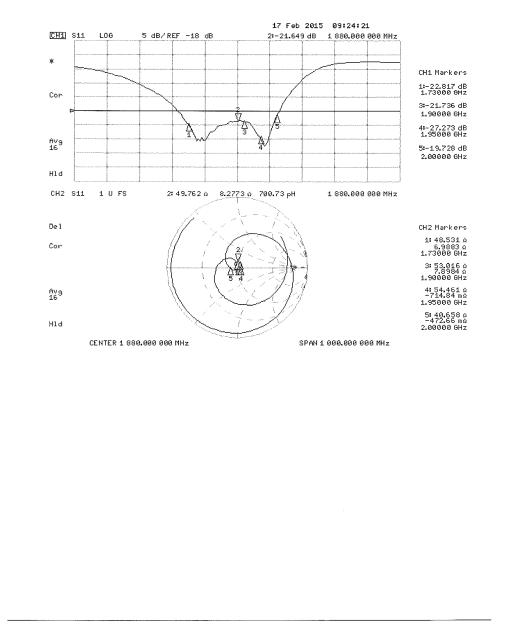
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD1880V3-1137_Feb15

Page 4 of 7

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 57 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		. ugo or or oo
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Impedance Measurement Plot



Certificate No: CD1880V3-1137_Feb15

Page 5 of 7

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕕 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Daga 59 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Page 58 of 66
2016 PCTEST Engineering Laboratory, Inc.				REV 3.1.M

DASY5 E-field Result

Date: 17.02.2015

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1137

Communication System: UID 0 - CW ; Frequency: 1880 MHz, Frequency: 1730 MHz Medium parameters used: σ = 0 S/m, ϵ_r = 1; ρ = 1000 kg/m³ Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: ER3DV6 SN2336; ConvF(1, 1, 1); Calibrated: 31.12.2014;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 12.09.2014
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole E-Field measurement/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 145.1 V/m; Power Drift = -0.01 dB Applied MIF = 0.00 dB RF audio interference level = 39.10 dBV/m Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 MZ	Grid 3 M2
38.62 dBV/m	38.99 dBV/m	38.92 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
36.52 dBV/m	36.82 dBV/m	36.81 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.84 dBV/m	39.1 dBV/m	39.07 dBV/m

Certificate No: CD1880V3-1137_Feb15

Page 6 of 7

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 59 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 59 01 00
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Dipole E-Field measurement/E-Scan - 1730MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 158.0 V/m; Power Drift = -0.01 dB

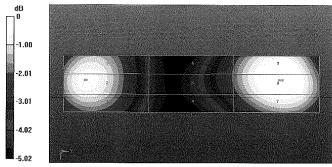
Applied MIF = 0.00 dB

RF audio interference level = 39.90 dBV/m

Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
39.02 dBV/m	39.39 dBV/m	39.32 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
37.42 dBV/m	37.87 dBV/m	37.86 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
39.53 dBV/m	39.9 dBV/m	39.87 dBV/m



0 dB = 90.20 V/m = 39.10 dBV/m

Certificate No: CD1880V3-1137_Feb15

Page 7 of 7

FCC ID: ZNFL53AL		IAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 60 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Tage 00 01 00
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15. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

Please note that the M-rating for this equipment only represents the field interference possible against a hypothetical and typical hearing aid. The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 61 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 01 01 00
© 2016 PCTEST Engineering Laboratory, Inc.			REV 3.1.M 05/09/2016	

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FCC ID: ZNFL53AL		HAC (RF EMISSIONS) TEST REPORT	🕒 LG	Reviewed by: Quality Manager
Filename:	Test Dates:	EUT Type:		Page 62 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 02 01 00
2016 PCTEST Engineering Laboratory, Inc.			REV 3.1.M 05/09/2016	

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Filename:	Test Dates:	EUT Type:		Page 63 of 66
0Y1605060893-R1.ZNF	05/09/2016 - 05/11/2016	Portable Handset		Fage 05 01 00
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